

SRD1000 with improved reference points for thermometry below 1 K

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Introduction

SRD1000 devices support 10 reference temperatures between 10 mK and 1200 mK for calibrations on the PLTS-2000

Device detects the superconductive transitions of samples of various materials to establish the reference temperatures

Prototype devices were evaluated by several institutes for metrology in Europe¹

For a new series of devices we developed improved preparation methods of the reference samples

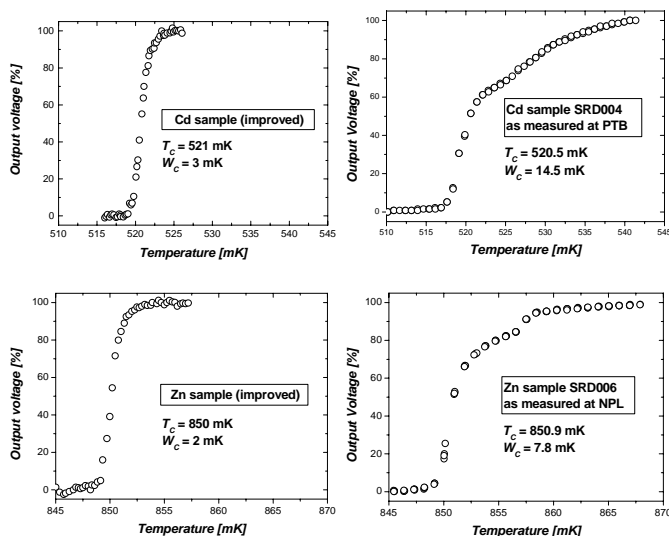
Preparation improved Cd and Zn samples

Samples were spark cut from high purity single crystals

Copper-sulphate etch removes interaction area cutting process

Omitting varnish from attachment process reduces mechanical stress

Comparison improved Cd and Zn with prototype samples



Transition temperatures T_c and widths W_c of SRD1000 prototypes and the new series

reference material	nominal T_c [mK]	W_c prototypes [mK]	W_c new series [mK]
W	15	< 0.2	< 0.2
Be	22	< 0.3	< 0.3
Ir ₈₀ Rh ₂₀	30	0.7 - 1.2	0.3 - 1
Ir ₉₂ Rh ₀₈	65	0.7 - 1	0.3 - 1
Ir	98	0.3 - 1	0.3 - 1
AuAl ₂	145	0.4 - 0.7	0.3 - 0.6
AuIn ₂	208	0.5 - 3	0.5 - 1
Cd	520	12 - 15	2 - 4
Zn	850	5 - 16	2 - 3
Al	1180	2 - 4	2 - 4

Conclusion

New preparation methods reduce W_c of Cd and Zn samples by factor of 4

Reduced W_c enables more accurate determination of reference temperatures

Sample improvements will be implemented in a new series of SRD1000 devices

Further information

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Web page: <http://www.xs4all.nl/~hdleiden/srd1000>

Financial support

European Commission, Measurement and Testing activity of the Competitive and Sustainable Growth programme, contract number G6RD-CT-1999-00119

Reference

1. S. Schöttl et al., this symposium